Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/878,519	BEAN ET AL.
Examiner	Art Unit
Nhan T. Tran	2615

SEARCHED				
Subclass	Date	Examiner		
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	Subclass	Subclass Date		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
UPDATED EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT)	10/5/2005	NT
348/157, 231, 333 (text search only - see search history printout)	10/6/2005	NT